

**Search Notes**

Application/Control No.

10/584,329

Examiner

SEAN M. MICHALSKI

Applicant(s)/Patent under  
Reexamination

TOYAMA, HIDEO

Art Unit

3724

**SEARCHED**

Class	Subclass	Date	Examiner
30	254	6/19/2008	SMM
200	277.2	6/19/2008	SMM

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Consulted with Jason Prone and Hwei-Siu Payer (PRIMARIES CLASS 30)	6/19/2008	SMM
Text searched magnet\$4 within 30; text searched for (plier scissor tool) with (magnet\$4) with (bias) and similar pure text-	6/19/2008	SMM